

# PRELIMINARY DATA SHEET

# GD74F125 QUAD BUFFER (TRI-STATE)

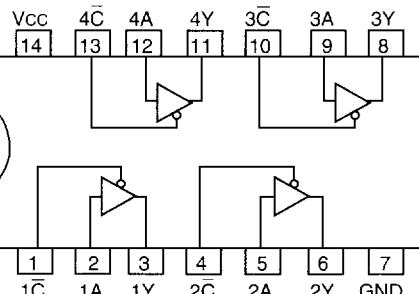
## Description

The GD74F125 contains 4 buffers with 3-State outputs and is provided with an output control input ( $\bar{C}$ ) which is independent for each buffer.

## Function Table (each gate)

Inputs	Outputs
$\bar{C}$	A
L	L
L	H
H	X
X: Immaterial	
Z: High Impedance	
Output is off (disabled) when $\bar{C}$ is high	

## Pin Configuration



Package Type: 14 DIP, 14 SOP Available

## Recommended Operating Conditions

- Free Air Ambient Temperature..... 0°C to 70°C
- Supply Voltage ..... 4.5°C to 5.5°C

## Absolute Maximum Ratings

- Storage Temperature ..... -65°C to 150°C
- Ambient Temperature Under Bias ..... -55°C to 125°C
- Junction Temperature Under Bias ..... -0.5°C to 175°C
- $V_{CC}$  Voltage ..... -0.5 V to 7.0 V
- Input Voltage ..... -5.0 V to 7.0 V
- Input Current ..... -30 mA to 5.0 mA
- Output Voltage ..... -0.5 V to 5.5 V

Note: Absolute Maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**AC Characteristics**

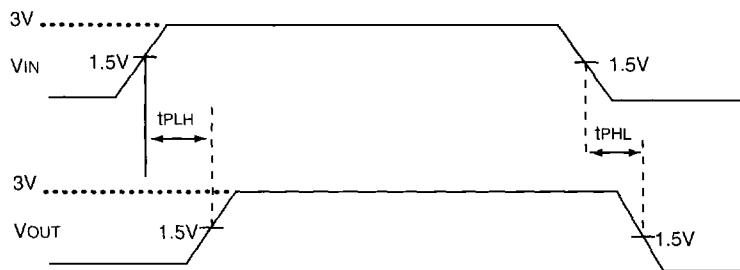
SYMBOL	PARAMETER	TEST CONDITION						UNIT	
		TA = 25°C VCC = 5.0 V CL = 50 pF			TA = 0 ~ 70°C VCC = 5V ± 10% CL = 50 pF				
		Min	Typ	Max	Min	Typ	Max		
tPLH	Propagation Delay	2.0	4.0	6.0	2.0	—	6.5	ns	
tPHL		3.0	4.6	7.5	3.0	—	8.0	ns	
tPZH	Propagation Delay	3.5	4.7	7.5	3.0	--	8.5	ns	
tPZL		3.5	5.3	8.0	3.5	--	9.0	ns	
tPHZ	Output Disable Time	1.5	3.9	5.5	1.5	--	6.0	ns	
tPLZ		1.5	4.0	6.0	1.5	--	6.5	ns	

**DC Electrical Characteristics** over recommended operating free-air temperature range

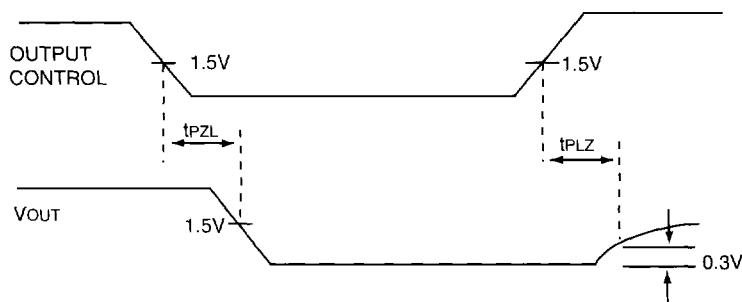
SYMBOL	PARAMETER	TEST CONDITIONS	Min	Typ	Max	UNIT	V <sub>CC</sub>	CIRCUIT
V <sub>IH</sub>	Input High Voltage	-----	2.0			V		
V <sub>IL</sub>	Input Low Voltage	-----			0.8	V		
V <sub>CD</sub>	Input Clamp Diode Voltage	I <sub>IN</sub> = -18mA			-1.2	V	Min	See FIG. 1
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -3mA I <sub>OH</sub> = -12mA I <sub>OH</sub> = -3mA I <sub>OH</sub> = -15mA	2.4 2.0 2.7 2.0			V	4.5 4.5 4.75 4.75	See FIG. 2
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 64mA			0.55	V	Min	
I <sub>I</sub>	Input High Current Breakdown Test	V <sub>IN</sub> = 7.0 V			100	μA	0.0	See FIG. 3
I <sub>IH</sub>	Input High Current	V <sub>IN</sub> = 2.7 V			20	μA	Max	
I <sub>IL</sub>	Input Low Current	V <sub>IN</sub> = 0.5 V			-20	μA	Max	
I <sub>OZH</sub>	Tri-State Output Off Current (High)	V <sub>OUT</sub> = 2.7 V			50	μA	Max	See FIG. 4
I <sub>OZL</sub>	Tri-State Output Off Current (Low)	V <sub>OUT</sub> = 0.5 V			-50	μA	Max	
I <sub>OS</sub>	Output Short Circuit Current	V <sub>OUT</sub> = 0 V	-100		-255	mA	Max	See FIG. 5
I <sub>CCH</sub> I <sub>CCL</sub> I <sub>CCZ</sub>	Supply Current	V <sub>OUT</sub> = High V <sub>OUT</sub> = Low V <sub>OUT</sub> = High Z		18.5 31.7 27.6	24.0 40.0 35.0	mA	Max	See FIG. 6

\* For I<sub>OS</sub>, Not more than one output should be shorted at a time, and duration should not exceed one second.

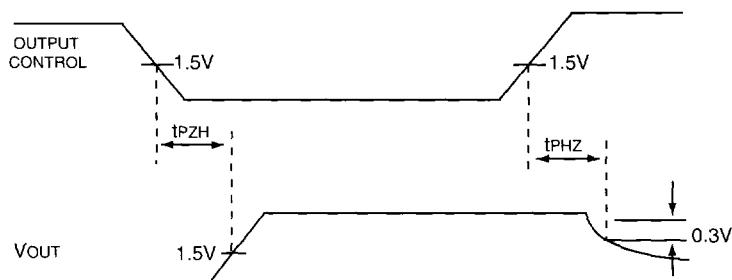
## Waveform Of Functions



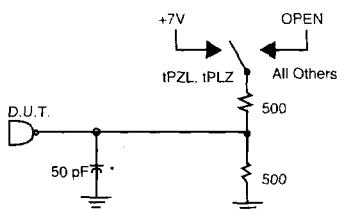
## 3-State Output Low Enable and Disable Times



## 3-State Output Low Enable and Disable Times



## AC Test Circuit



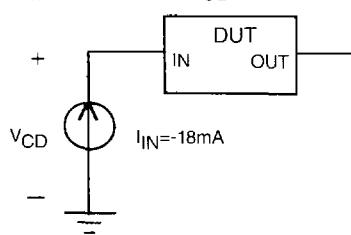
### Input Condition

Frequency : 1.0 MHZ  
Duty Cycle : 50%  
Rising Time : 2.5 ns  
Falling Time : 2.5 ns  
Amplitude : 0 to 3V

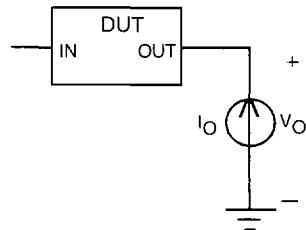
\* Include Jig And Probe Capacitance

## DC Test Circuit

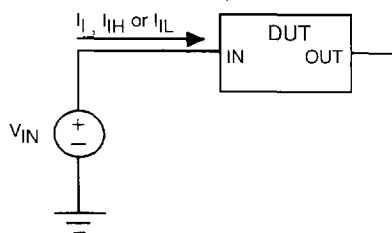
**FIG. 1  $V_{CD}$  Test**  
(force  $I_{IN}$  and measure  $V_{CD}$ )



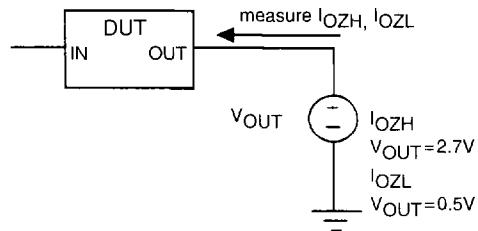
**FIG. 2  $V_{OH}$  &  $V_{OL}$  Test**  
(force  $I_O$  and measure  $V_{OH}$  or  $V_{OL}$ )



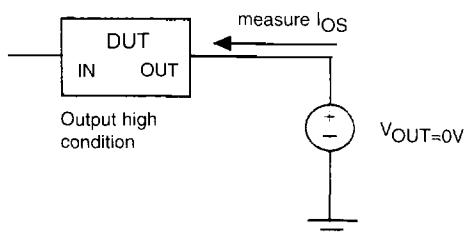
**FIG. 3  $I_I$ ,  $I_{IH}$  &  $I_{IL}$  Test**  
(force  $V_{IN}$  and measure  $I_I$ ,  $I_{IH}$  or  $I_{IL}$ )



**FIG. 4  $I_{OZH}$  &  $I_{OZL}$  Test**



**FIG. 5  $I_{OS}$  Test**



**FIG. 6  $I_{CC}$  Test**

